

The new Easy S-series

Smart – Small – Sizeable

Low Power Marketing

Launch: June 2026



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Infiniteon's Easy S-series modules: Benchmark packages in the power semiconductor world, also for automotive industry

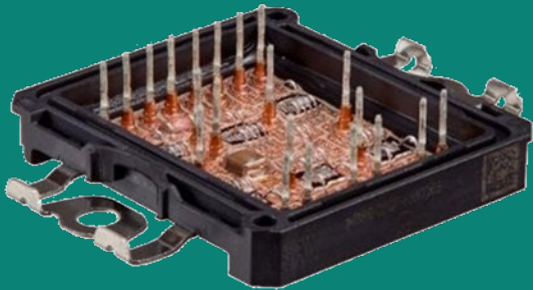


The **EasyPACK™ S** family is the best choice for customers who are looking for a **flexible and scalable** power module solution. We offer the broadest package and technology portfolio. The flexible pin grid system is a perfect fit for **customizing** layout and pinout.

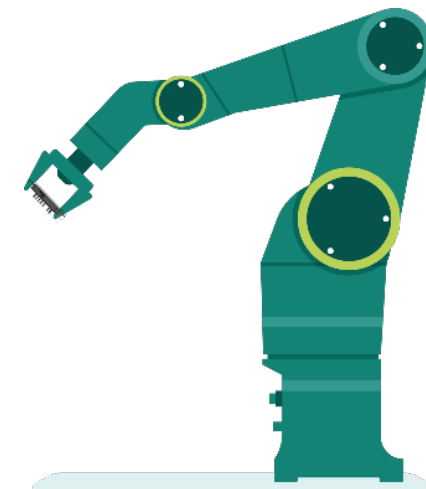
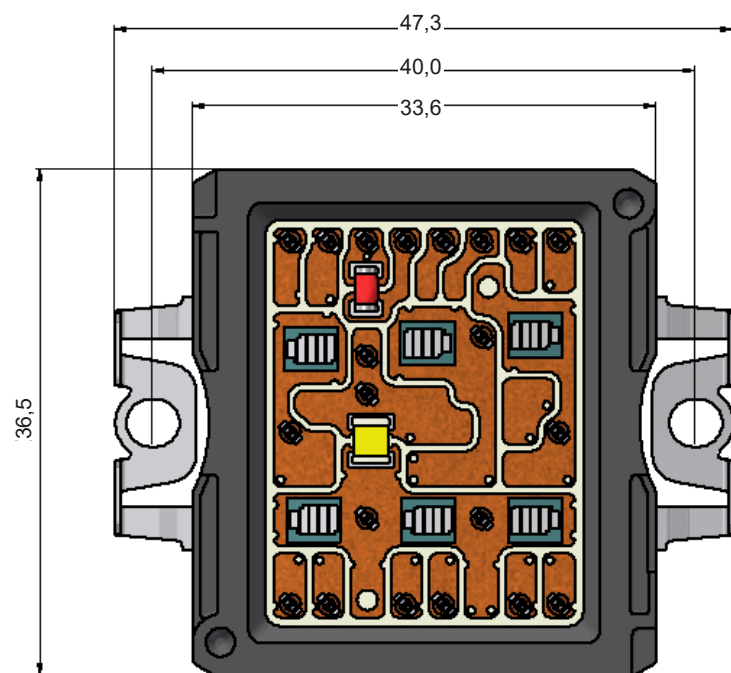
+75mio
DW in 2025

Advantages of Infineon's Easy S-series modules

- **High-Volume Production:** The EasyPACK™ family extension is designed to support high-volume production with a high degree of automated handling for customer efficiency.
- **Competitive Pricing:** Ensures price competitiveness against various market solutions, including topside-cooled devices and molded packages.
- **Future-Ready Design:** The EasyPACK™ family extension is prepared for integration with new chip technologies and can meet demanding lifetime requirements.



EasyPACK™ S – mechanical concept design



Target Requirements	
Packaging base area	~36,5 x 33,6 mm (36,5 x 47,3 mm incl. clamps)
Packaging height	~5,6 mm
Creepage distance pin->heat sink	12,4 mm
CTI value	600
Interconnection	High current PressFit pins
Operating temperature	175 °C
Manufacturing support 1	Alignment holes for automated handling
Manufacturing support 2	Gripping areas on module frame
Qualification	AQG324
Sample availability	yes
Target SOP	Q2/2026

Automated Processing Made Easy: Features of EasyPACK™ S

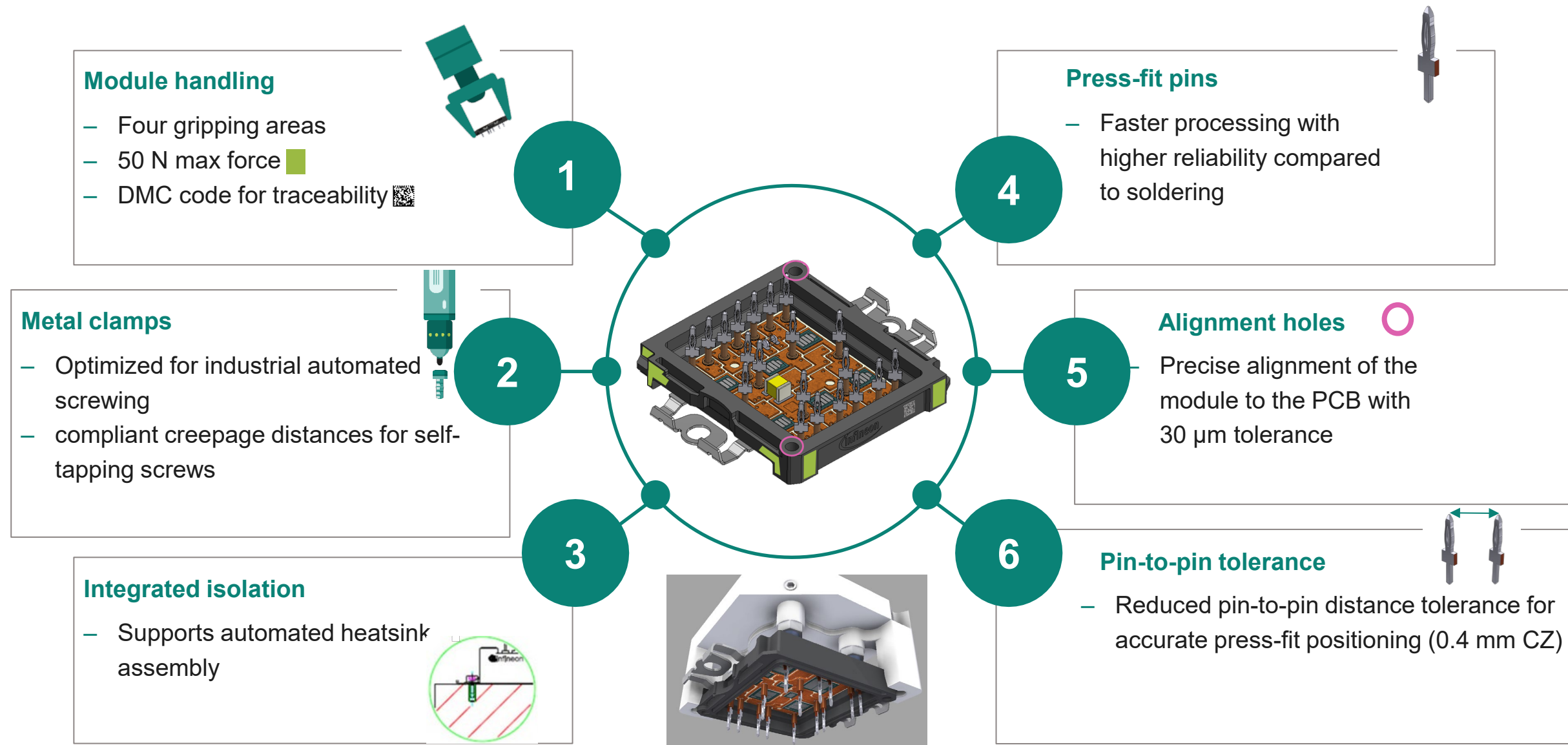
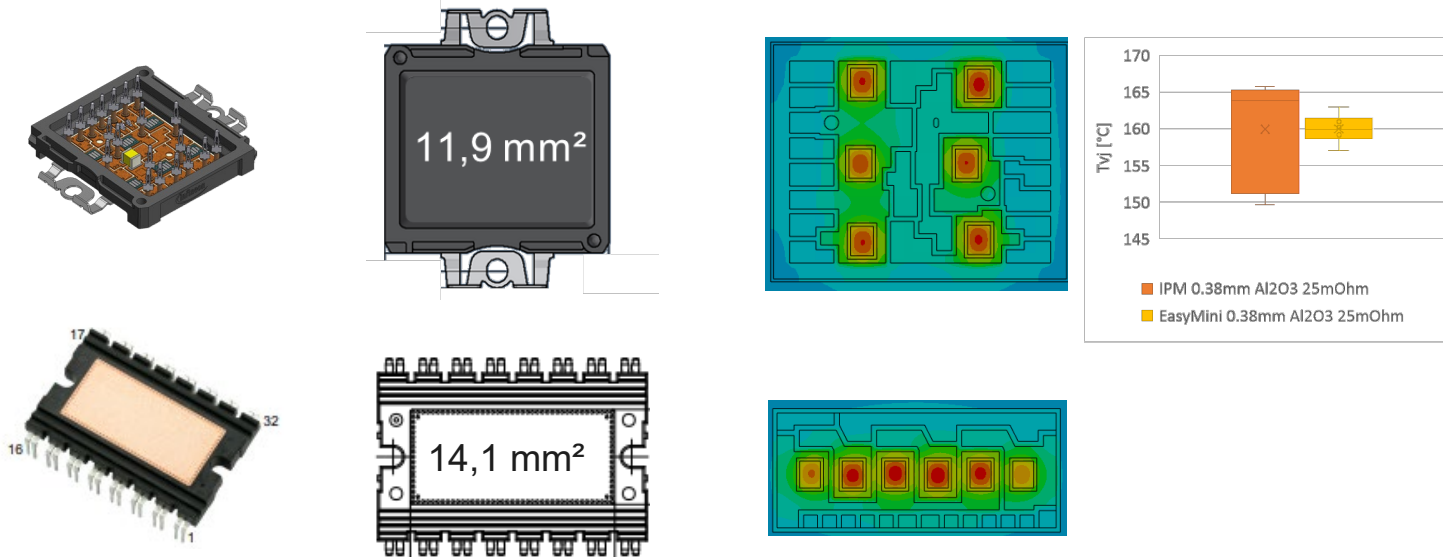


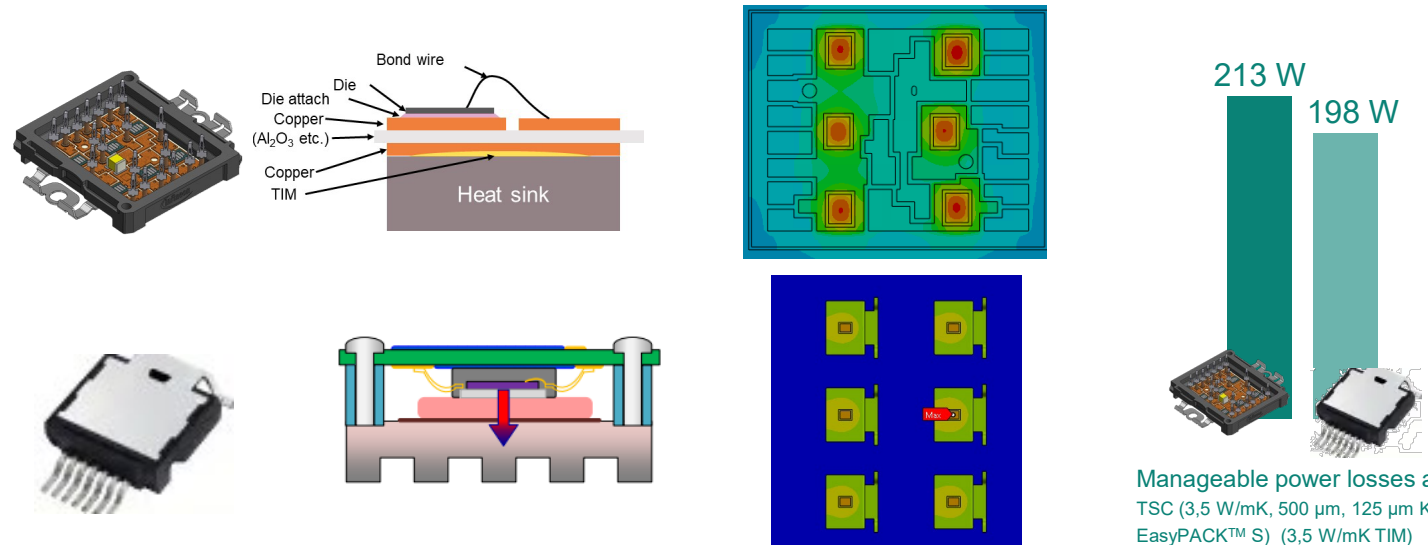
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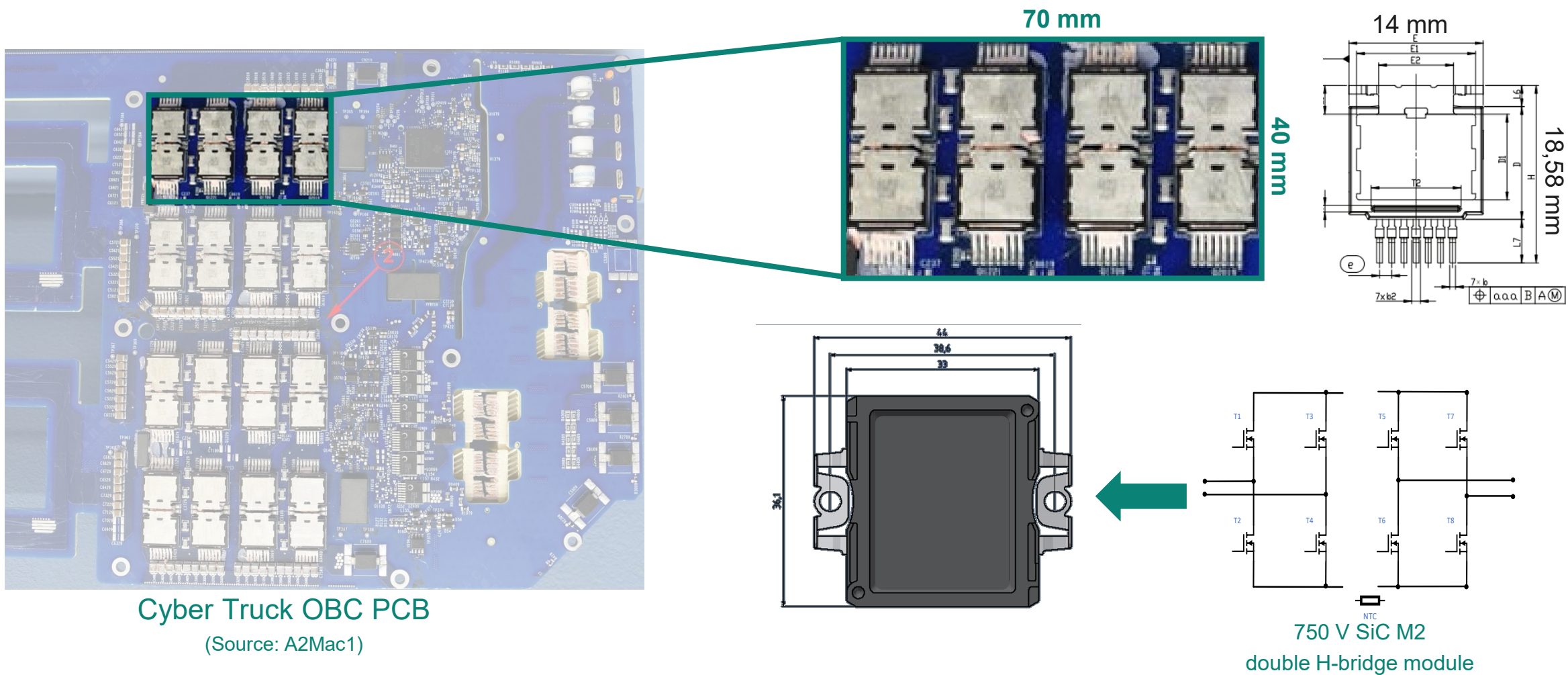
- EasyPACK™ S reaches the lower max. temperature under same conditions.
- EasyPACK™ S chip temperature is homogenous balanced.

- ➔ efficient & easier customer design
- ➔ homogeneous lifetime consumption in EasyPACK™ S
- ➔ lower thermo-mechanical stress on substrate



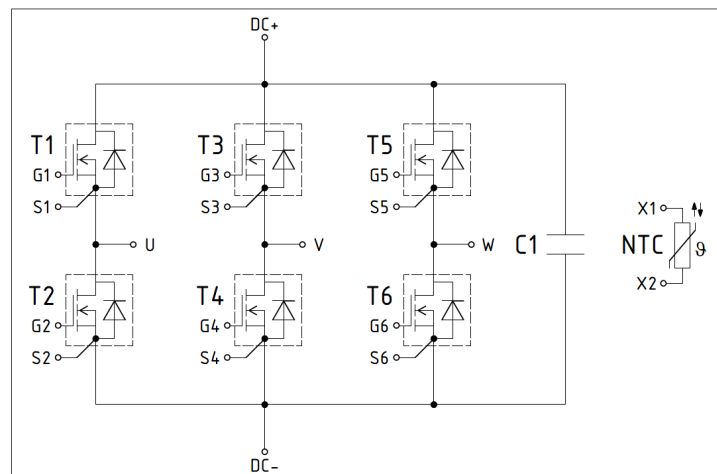
- ➔ higher output power with EasyPACK™ S for the same die size @ 30% less base area.
- ➔ smaller chip size for the same power rating with EasyPACK™ S

EasyPACK™ S can significantly reduce the PCB area

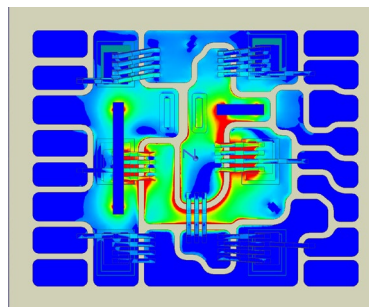
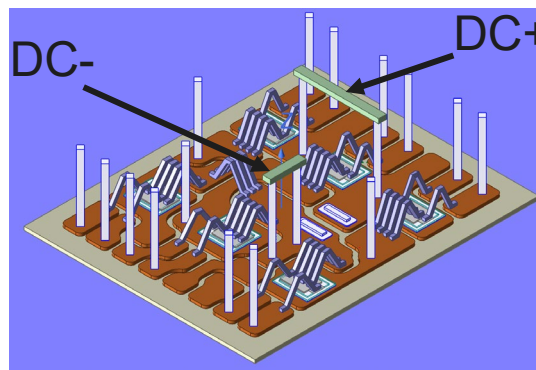


Key Data EasyPACKTM S-series lead Type: FS25MR12SM2_A

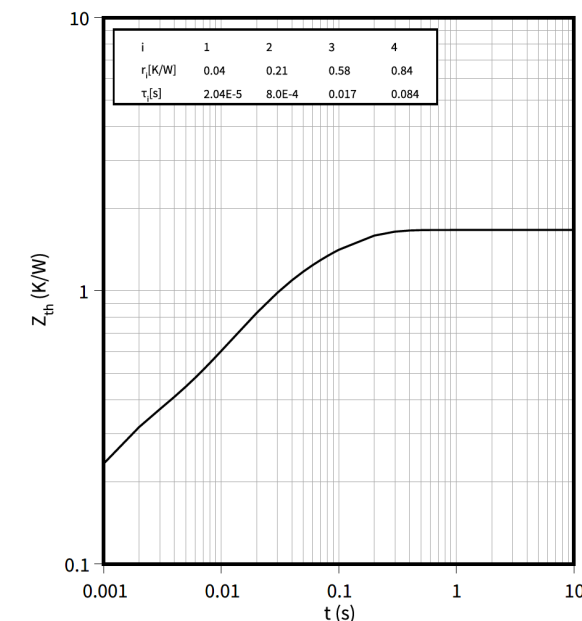
Circuit Diagram:



- Integrated decoupling capacitor
- Integrated NTC



- L_s : 10 nH*
 - Low R_{gint} for high switching capability
- * (w/o considering the snubber)



- $R_{th,jh}$: 1,7 K/W
- Al₂O₃ DCB*
- Losses up to 50 W/die
- Available also with high performance ceramic

* $R_{th,jh}$ with high performance ceramic comes down to 1 K/W

CoolSiC™ MOSFETs now even better: G2 comparison over G1

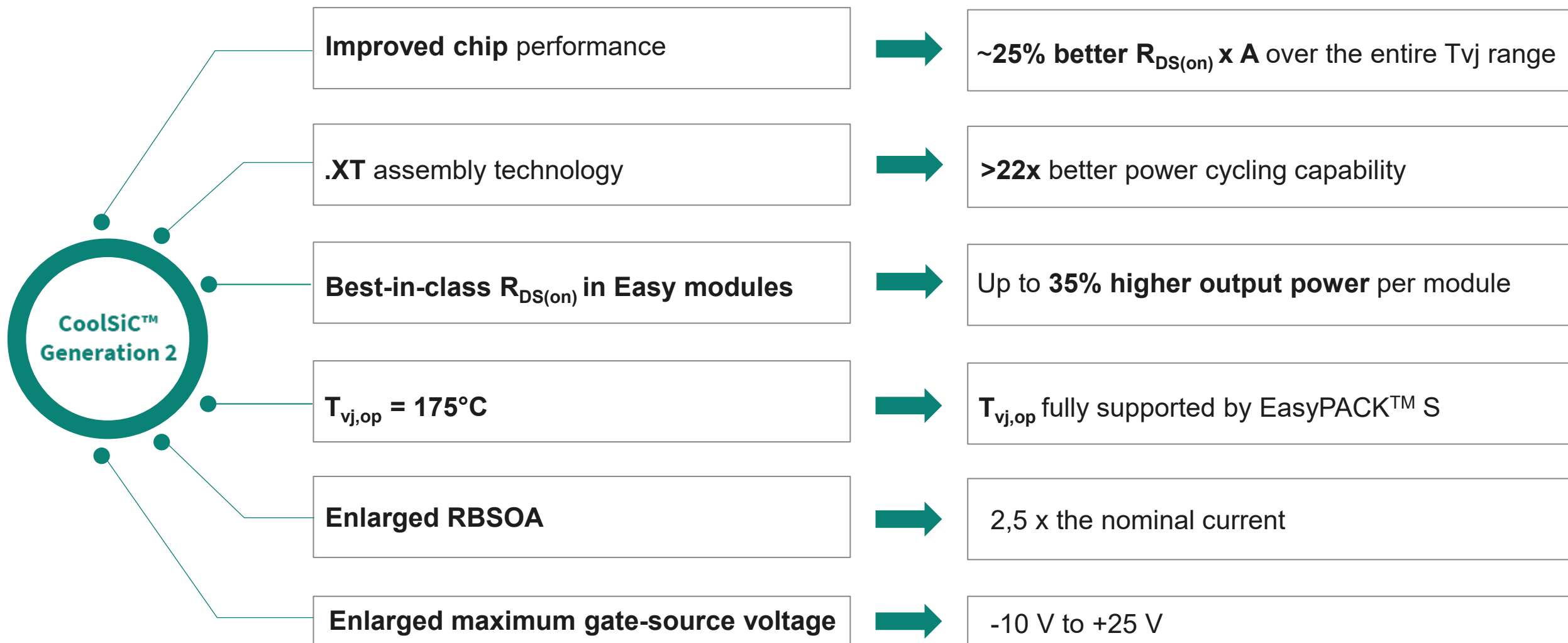


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Comparison of Basic Qualification Test Plan

Automotive grade AQG324 compliant qualification	Test Description	Abbr.	Industrial grade
1.000 h $V_{CE} = 0,8 \times V_{CES}$ (DC) $T_{vj} = T_{vj\ op\ max}$	High Temperature Reverse Bias	HTRB	1.000 h $V_{CE} = 0,9 \times V_{CES}$ (DC) $T_{vj} = T_{vj\ op\ max}$
1.000 h $V_{GE} = \pm 20\ V^{*)}$ (DC) $T_a = T_{vj\ op\ max}$	High Temperature Gate Bias	HTGB	1.000 h $V_{GE} = \pm 20\ V^{*)}$ (DC) $T_a = T_{vj\ op\ max}$
1.000 h $T_a = 85\ ^\circ C$; RH = 85% $V_{CE} = 80\ V$ (DC)	High Humidity High Temperature Reverse Bias	H3TRB	1.000 h $T_a = 85\ ^\circ C$; RH = 85% $V_{CE} = 80\ V$ (DC)
1.000 h $T_a = 85\ ^\circ C$; RH = 85 % $V_{CE} = 0,8 \times V_{CES}$ (DC)	High Voltage High Humidity High Temperature Reverse Bias*	HV-H3TRB **)	1.000 h $T_a = 85\ ^\circ C$; RH = 85 % $V_{CE} = 0,8 \times V_{CES}$ (DC)
$N_{cyc} = N_{cyc,\ target}$ $\Delta T_{vj} = @\ two\ \Delta T\ \&\ two\ t_{on}$ $T_{vj\ max} = T_{vj\ op\ max}$	Power Cycling	PC	$N_{cyc} = N_{cyc,\ target}$ $\Delta T_{vj} = @\ one\ \Delta T\ ***)$ $T_{vj\ max} = T_{vj\ op\ max}$
1.000h $T_a = T_{stg,\ max}$	High Temperature Storage	HTS	1.000h $T_a = T_{stg,\ max}$
1.000h $T_a = T_{stg,\ min}$	Low Temperature Storage	LTS	-
Different profiles for vibrational tests → e.g. wide – band random; 8 h each direction (x, y, z) $f = 5 / 10 / 55 / 180 / 300 / 360 / 1000 / 2000$ [Hz] $PSD = 0,884 / 20 / 6,5 / 0,25 / 0,25 / 0,14 / 0,14 / 0,14$ [g ² /Hz] $a = 30,8\ m/s^2$ (r.m.s.)	Vibration	VIB	Sine Sweep 5 h each direction (x, y, z) $f = 5...200$ Hz $f1 = 5...13$ Hz: $A = 7,5\ mm$ (const.) $f2 = 13...200$ Hz: $a = 50\ m/s^2$ $v = 1$ Octave/min.
60 shocks; 10 in each direction ($\pm x, \pm y, \pm z$) $a = 500\ m/s^2$ (peak) $t = 6\ ms$	Vibration (Shock)	MS	-
1.000 Cycles, mounted $T_a = -40\ ^\circ C$ to $+125\ ^\circ C$	Thermal Shock Test (two chamber)	TST	50 Cycles, unmounted $T_a = -40\ ^\circ C$ to $+125\ ^\circ C$ (or $150\ ^\circ C$)

*) Typical value. May differ for e.g. SiC technology

**) Only if applicable

**) For a released power cycling curve, PC at one ΔT is performed, as a confirmation of the PC curve of the respective chip technology

Reliability Qualification acc. to the Automotive Qualification Guideline (AQG 324)

Main deltas to standard industrial qualification test plan

- › **No differences:** Chip storage tests (HTGB; H3TRB; HV-H3TRB)

Only difference:

- HTRB @ $V_{ce} = 0,8 \times V_{ces, max}$
- Industrial grade typically $V_{ce} = 0,9 \times V_{ces, max}$

- › Additional tests:
 - LTS (low T - storage)
 - MS (mechanical shock)

- › Expanded Tests:
 - **1000** cycles TST @ T_{stg} (industrial grade 50 cycles)
 - PC: 2 different ΔT and 2 different t_{on}
 - Different profiles for vibrational testing



AQG 324



ECPE Guideline AQG 324

**Qualification of Power Modules for Use in Power Electronics
Converter Units in Motor Vehicles**

Release no.: 03.1/2021

Release date: 31.05.2021

Contact: ECPE European Center for Power Electronics e.V.
Dipl.-Phys. Thomas Harder
Landgrabenstrasse 94
90443 Nuremberg, Germany
Email thomas.harder@ecpe.org
Phone (+49) 911 8102 880

Standard documentation

Retention/Submission Requirements Table 4.2

(Normative)

[NOTE: Table 4.2 lists submission and retention requirements. Mandatory and applicable requirements for a PPAP record are defined in the PPAP manual and by the customer.]

<u>Requirement</u>		<u>Submission Level</u>				
		<u>Level 1</u>	<u>Level 2</u>	<u>Level 3</u>	<u>Level 4</u>	<u>Level 5</u>
1.	Design Record	R	S	S	*	R
	- for proprietary components/details	R	R	R	*	R
	- for all other components/details	R	S	S	*	R
2.	Engineering Change Documents, if any	R	S	S	*	R
3.	Customer Engineering approval, if required	R	R	S	*	R
4.	Design FMEA	R	R	S	*	R
5.	Process Flow Diagrams	R	R	S	*	R
6.	Process FMEA	R	R	S	*	R
7.	Control Plan	R	R	S	*	R
8.	Measurement System Analysis Studies	R	R	S	*	R
9.	Dimensional Results	R	S	S	*	R
10.	Material, Performance Test Results	R	S	S	*	R
11.	Initial Process Studies	R	R	S	*	R
12.	Qualified Laboratory Documentation	R	S	S	*	R
13.	Appearance Approval Report (AAR), if applicable	S	S	S	*	R
14.	Sample Product	R	S	S	*	R
15.	Master Sample	R	R	R	*	R
16.	Checking Aids	R	R	R	*	R
17.	Records of Compliance	R	R	S	*	R
	With Customer-Specific Requirements					
18.	Part Submission Warrant (PSW)	S	S	S	S	R
	Bulk Material Checklist (see 4.1 above)	S	S	S	S	R

S = The organization shall submit to the customer and retain a copy of records or documentation items at appropriate locations.

R = The organization shall retain at appropriate locations and make available to the customer upon request.

* = The organization shall retain at appropriate locations and submit to the customer upon request.

PPAP level 3 is a standard documentation provided for products with Quality Requirement Category „automotive“

No PPAP is provided for industrial products.

For industrial products, standard documentation can be found on our web pages:

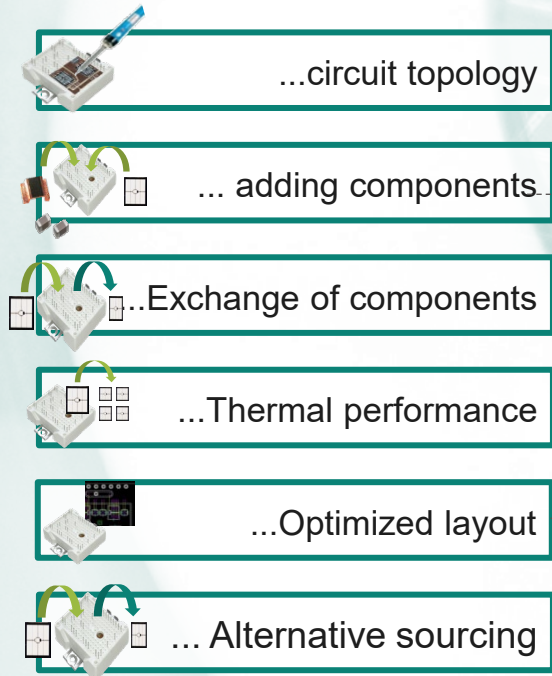
- Data Sheet
- Product Qualification Report
- MCDS

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Easy module solution is based on flexibility and customization, supports special application requirements and customer demands

Customization through...



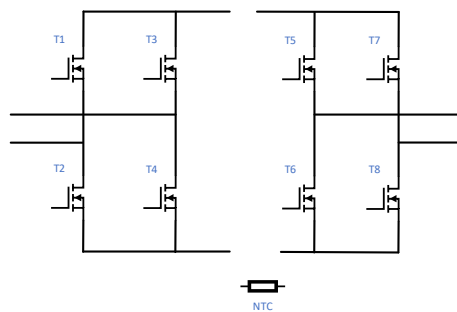
Easy modules enable customers differentiation

Flexibility with our variety of chipsets

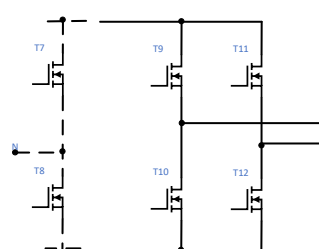
TRENCHSTOP™ IGBT7 1200 V ✓	Trench/Fieldstop IGBT4 1200 V ✓	TRENCHSTOP™ 5 H5, 650 V ✓
EC7 Diode 1200 V ✓	Rapid1 Diode 650 V ✓	CoolSiC™ Schottky Diodes 650 V / 1200 V ✓
CoolSiC™ MOSFET M1H 1200 V ✓	CoolSiC™ MOSFET M2 1200 V ✓	CoolSiC™ MOSFET M2 750 V ✓
CoolMOS™ CFD7A 650 V ✓		

✓ available ⌚ upcoming

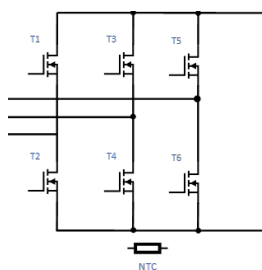
Planned Easy S-series portfolio



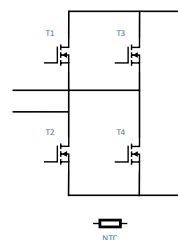
	EasyPack™ S	Spec	Technology
Module 1	T1-T8	750 V ~40 mΩ	SiC MOSFET
Module 2	T1-T8	750 V ~22 mΩ	SiC MOSFET



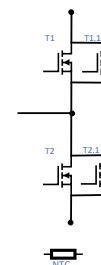
	EasyPack™ S	Spec	Technology
Module 1	T7-T8 T9-T12	1200 V 15-17mΩ 1200 V ~50 mΩ	SiC MOSFET SiC MOSFET
Module 2	T7-T8 T9-T12	750 V 22 mΩ 750 V ~40 mΩ	SiC MOSFET SiC MOSFET



	EasyPack™ S	Spec	Technology
Module 1	T1-T6	1200 V ~25 mΩ	SiC MOSFET
Module 2	T1-T6	1200 V ~40 mΩ	SiC MOSFET
Module 3	T1-T6	1200 V ~60 mΩ	SiC MOSFET



	EasyPack™ S	Spec	Technology
Module 1	T1-T4	750 V 40 mΩ	SiC MOSFET
Module 2	T1-T4	750 V 22 mΩ	SiC MOSFET
Module 3	T1-T4	1200 V 25 mΩ	SiC MOSFET
Module 4	T1-T4	1200 V ~40 mΩ	SiC MOSFET



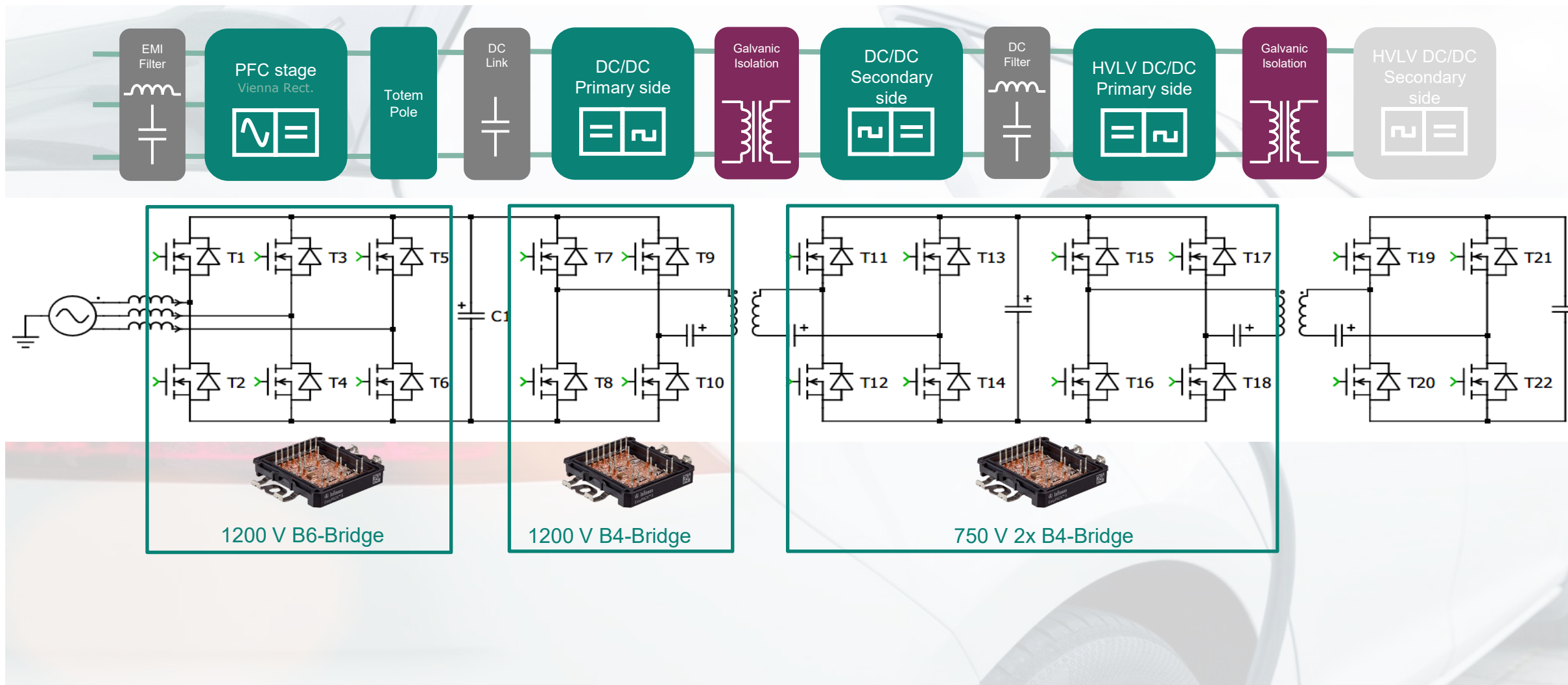
	EasyPack™ S	Spec	Technology
Module 1	T1- T2.1	1200 V 13 mΩ	SiC MOSFET
Module 2	T1- T2.1	750 V ~11 mΩ	SiC MOSFET
Module 3	T1- T2.1	750 V ~4 mΩ	SiC MOSFET

ATV qualified chip set

Voltage	R _{dson} / current rating	Technology
650 V	35, 75, 99 mOhm	CFD7A; CoolMOS
650 V	50 A	IGBT 5 H5
650 V	40 A	Rapid 1 Diode
650 V	16 A	SiC G5 Diode
750 V	8, 25, 46	M2 SiC
1200 V	33, 55, 73 mOhm	M1H SiC
1200 V	15*, 25, 40*, 60*,	M2 SiC
1200 V	20 A	SiC G5 Diode
1200 V	100 A, 50 A	IGBT 7
1200 V	100 A, 50 A, 11A	EC7 Diode

* planned

Easy S-series OBC proposal



Timeline of Easy S-series portfolio development

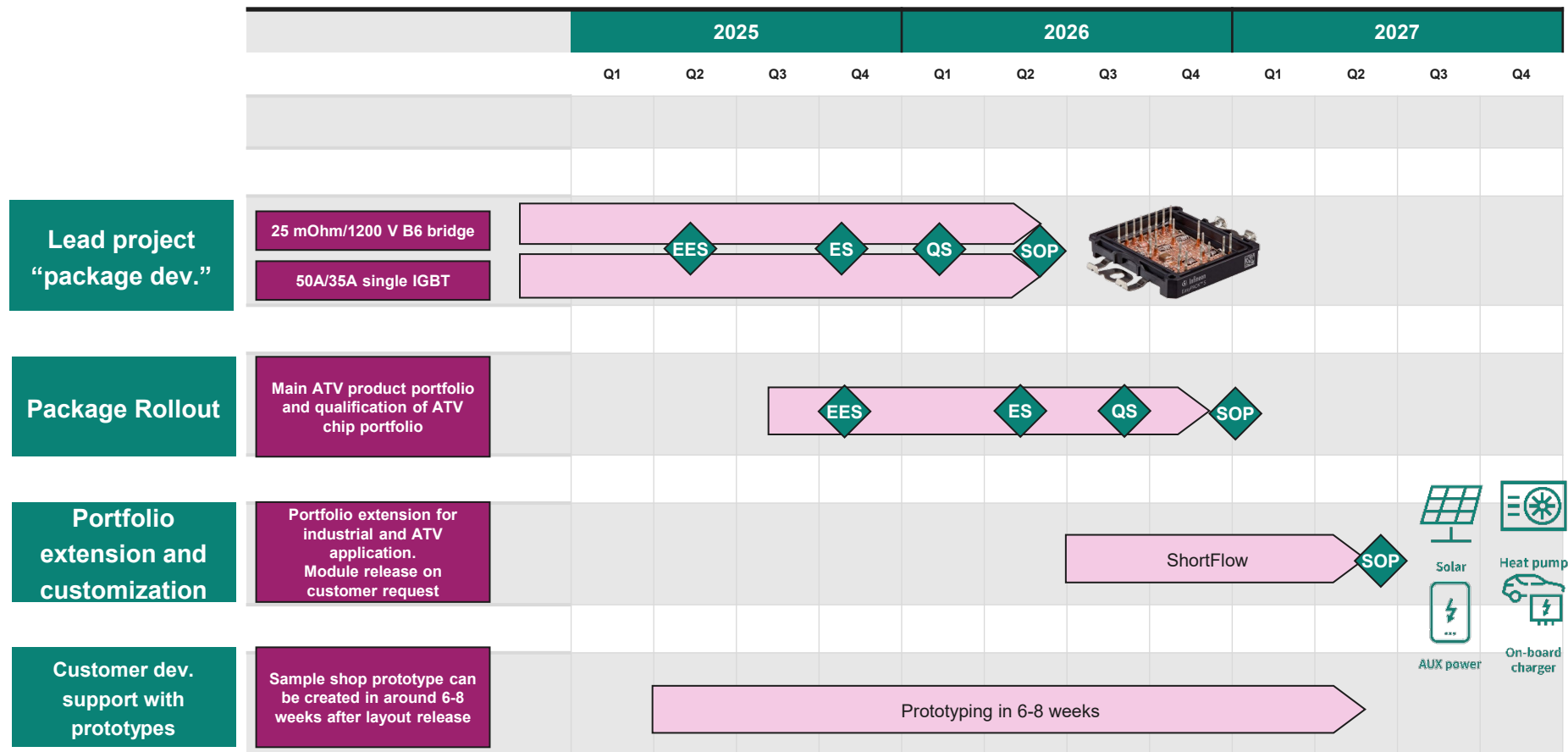


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